

PA-IDC

<b>QUERY CONTROL FORM</b>			<b>RTIS USE ONLY</b>
Application No.	Prepared by	Tracking Number	
Examiner-GAJ <u>Bruce - 2882</u>	<u>JM</u> 1/8/04	Week Date	<u>05875029</u> <u>12/12/03</u>
	No. of queries	<u>1</u>	

**JACKET**

- |                      |                        |                    |                |
|----------------------|------------------------|--------------------|----------------|
| a. Serial No.        | f. Foreign Priority    | k. Print Claim(s)  | p. PTO-1449    |
| b. Applicant(s)      | g. Disclaimer          | l. Print Fig.      | q. PTOL-85b    |
| c. Continuing Data   | h. Microfiche Appendix | m. Searched Column | r. Abstract    |
| d. PCT               | i. Title               | n. PTO-270/328     | s. Sheets/Figs |
| e. Domestic Priority | j. Claims Allowed      | o. PTO-892         | t. Other       |

- SPECIFICATION**
- a. Page Missing
  - b. Text Continuity
  - c. Holes through Data
  - d. Other Missing Text
  - e. Illegible Text
  - f. Duplicate Text
  - g. Brief Description
  - h. Sequence Listing
  - i. Appendix
  - j. Amendments
  - k. Other

**MESSAGE** PTO 1449: Please either initial or  
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- CLAIMS**
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  - k. Other

THANK you  
initials JM

**RESPONSE** \_\_\_\_\_

initials

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<b>INFORMATION DISCLOSURE CITATION</b> <small>(Use additional sheets if necessary)</small>	Docket Number (Optional) <b>TWI-10820</b>	Application Number <b>09/629,407</b>
	Applicant(s) <b>Allan Rosenzwaig et al.</b>	
	Filing Date <b>August 1, 2000</b>	Group Art Unit <b>2876</b>

APR 30 2002

ATLANTA TRADEMARK OFFICE  
U.S. PATENT AND TRADEMARK OFFICE

U.S. PATENT DOCUMENTS

*EXAMINEE INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILED DATE

FOREIGN PATENT DOCUMENTS

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES	NO
	CA	WO 01/71325	09/27/2001	PCT	G01N	23/00		

OTHER DOCUMENTS  
*(Including Author, Title, Date, Pertinent Pages, Etc.)*

CB	E. Lüken et al., "Growth monitoring of W/Si X-ray multilayers by X-ray reflectivity and kinetic ellipsometry," SPIE, Vol. 2233, November 1994, pp. 327-332.

Examiner	Date Considered
<b>Examiner: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include Copy of this form with next communication to applicant.</b>	

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